EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	0	(retest\$3 with ((cell) adj select\$3)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:49
L3	0	(retest\$3 adj ((cell))) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:49
L4	4	(reselect\$3 adj ((cell))) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:50
L5	0	(select\$3 adj another adj (spare adj cell)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:51
L6	0	(another adj (spare adj cell)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:51
L7	0	(different adj (spare adj cell)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:51
L8	13	(different with (spare adj cell)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:51
L9	0	(another with (spare adj cell)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 08:51
S65	1755	714/25.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:45

S66	674	714/42.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 13:31
S67	280	714/54.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 14:47
S70	39	714/42.ccls. and bist	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:56
S71	27	("5255227" "5848077" "5896331" "5956350" "6000047" "6085334" "6141779" "6304989" "6408401" "6421794" "6425095" "6438046" "6446224" "6496947" "6505308" "6505313" "6535993" "6560740" "6640321").PN. OR ("6691252").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/06/05 13:43
S72	24	("20020108073" "4460997" "4701887" "5337318" "5355340" "5469389" "5506807" "5621691" "5831915" "5896328" "5999450" "6115300" "6134142" "6327197" "6366508" "6373758" "6408401" "6426902" "6445626" "6477662" "6496947" "6571348" "6691252" "6795942").PN. OR ("6928377").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/06/05 13:45
S73	8	("5541942" "5758056" "5764878" "6035432" "6385746" "6449704"). PN. OR ("6640321"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/06/05 14:35
S74	637	714/7.ccls.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/06/05 14:35
S75	14	714/42.ccls. and (built adj in adj self adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:56

S 85	25	S74 and (bist (built adj in adj self adj test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:58
S86	6	S67 and (bist (built adj in adj self adj test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:57
S87	28	S74 and (bist (built adj in adj self adj test\$3) (built-in adj self-test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 15:21
S88	3	S87 not S85	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 15:18
S89	20	714/711.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:58
S90	34	714/710.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:59
S91	252	714/718.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 16:03
S92	27	714/42.ccls. and ((built adj in adj self adj test\$3) (built-in adj self-test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 15:22
S93	13	S92 not S75	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/05 15:22

S94	15	("4325120" "4701919" "5555212" "5579484" "5724365" "5771195" "5808948" "5920515" "6065134" "6175936" "6199031" "6516430" "6516450").PN. OR ("6728910").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/06/05 16:43
S95	1	10/750961	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:50
S96	2072	(memory adj test\$3) and pin	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:51
S97	93	(memory adj test\$3) and (pin with (fail))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:51
S98	7	(US-20020120887-\$).did. or (US-6065134-\$ or US- 6728910-\$ or US-6085334- \$ or US-6928588-\$ or US- 6640321-\$ or US-6181614- \$).did.	US-PGPUB; USPAT	OR	OFF	2006/06/11 17:54
S99	0	S98 and manifactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:54
S100	6	S98 and manufactur\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:59
S101	0	S98 and post	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 17:59
S102	122	(memory adj test\$3) with post	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 18:04

S103	45	(memory adj test\$3) and (register with (redundant) with (row column))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/06/11 18:05
S104	51	714/25.ccls. and @pd> "20060530"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:04
S105	1	714/42.ccls. and bist and @pd> "20060418"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:03
S106	1	714/42.ccls. and (built adj in adj self adj test\$3) and @pd>"20060418"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:57
S107	284	714/54.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:57
S108	0	S107 and (bist (built adj in adj self adj test\$3)) and @pd>"20040930"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:57
S109	657	714/7.ccls.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/09/09 15:58
S110	0	S109 and (bist (built adj in adj self adj test\$3)) and @pd>"20060516"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/09/09 15:58
S111	1	714/711.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060221"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:22
S112	4	714/710.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060516"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:32
S113	17	714/718.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060523"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:35

S114	35	714/718.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060907"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:00
S115	7	714/710.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060815"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:03
S116	6	714/42.ccls. and bist and @pd>"20060704"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:03
S117	5	714/711.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060815"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/31 19:04
S118	104	714/25.ccls. and @pd> "20060907"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 08:01
S119	9	714/711.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060815"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:22
S120	14	714/710.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060815"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:32
S121	82	714/718.ccls. and (bist (built adj in adj self adj test \$3) (built-in adj self-test \$3)) and @pd>"20060907"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 06:35
S122	78	714/25.ccls. and @pd>"20070329"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/07 08:01

S123	21	("4325120" "4701919" "5555212" "5579484" "5724365" "5771195" "5808948" "5920515" "6065134" "6175936" "6199031" "6516430" "6516450").PN. OR ("6728910").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 10:25
S124	7	("20030072204" "20030117886" "20040109371" "6288940" "6295237" "6438044" "6728910"). PN. OR ("7352638"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 10:28
S125	1	("2004/0109371").URPN.	USPAT	OR	OFF	2008/04/15 10:28
S126	13	("20040117694" "20040205427" "20040237009" "6052798" "6065134" "6246618" "6366508" "6374370" "6462995" "6507524" "6667918" "6728910" "6928591"). PN. OR ("7257733"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 10:47
S127	2	("2004/0237009").URPN.	USPAT	OR	OFF	2008/04/15 10:55
S128	5	("20030101389" "4751656" "6026505" "6795942").PN. OR ("6928591").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 11:11
S129	38	("4757503" "5153880" "5243570" "5267205" "5267242" "5325333" "5337277" "5377146" "5424986" "5487040" "5553231" "5684740" "5764878" "5805789"). PN. OR ("6065134"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 12:07
S130	1	10/750961	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 12:24
S134	4	("6181614" "6643195" "6728910" "6801471"). PN. OR ("7062695"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/04/15 15:00

S135	2	"5327382".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/16 11:29
S136	2	"6144592".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/16 13:03
S137	2	"20040261049"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/04/16 13:05
S138	20	(testing adj (spare adj memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/04 10:00
S139	5	(checking adj (spare adj memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/04 10:03
S140	5	(checking adj (redundant adj memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/04 10:07
S141	87	(testing adj (redundant adj memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/04 10:08
S142	694	(test\$3 with memory) with (spare)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 00:56
S143	241	(test\$3 with semiconductor) with (spare)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 00:56
S144	332	cache with spare	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:01

S145	14	(test\$3 adj spare) with (semiconductor)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:03
S146	0	(test\$3 adj cell adj before adj use)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:15
S147	0	(test\$3 adj cell adj before adj using)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:15
S148	0	(test\$3 adj cell adj before adj store)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:16
S149	0	(test\$3 adj cell adj before adj storing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:16
S150	0	(test\$3 adj cell adj prior adj use)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:16
S151	30	(test\$3 adj cell adj prior)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:16
S152	6	(test\$3 with (cell adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:17
S153	0	(test\$3 adj (cell adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:20
S154	0	(test\$3 adj (spare adj cell adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:20

S155	0	(check\$3 adj (spare adj cell adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:20
S156	0	((spare adj cell adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:20
S157	0	((spare adj prior)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:20
S158	2	("5652725").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:21
S159	0	repeat\$3 with ((redundant spare) adj (row column) adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:30
S160	13	repeat\$3 with ((redundant spare) adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:30
S161	4	repeat\$3 with ((redundant spare) adj select\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:31
S162	280	repeat\$3 with ((cell) adj select\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:32
S163	57	(repeat\$3 with ((cell) adj select\$3)) and (semiconductor adj memory)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/08 01:32

6/8/08 9:40:48 AM